Thin Film High-Density Interconnect (HDI) Design Guidelines

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Abstract

The design of single- or double-sided Thin Film high density multi-layer substrates depends on a wide range of rules. This paper is intended to be a comprehensive roadmap of the design process, with a focus on the selection of materials, films, and extensive range of options. The purpose is to educate the circuit user on Thin Film High Density Interconnects (HDI) and the benefits of design performance. These benefits are achieved through enhanced control of impedance signal routing, size, noise, and response conditioning using Thin Film design concepts. This paper reviews the flow selection and critical decisions needed to use HDI technology.

Introduction

High-Density Interconnect products can be a complicated process for design engineers. This guideline has been written to simplify the design process by providing a useful tool to the engineering community. Whether the requirements are for simple resistor networks, integrated resistor-capacitor networks, multilayer components, custom thin film networks on Alumina (Al₂O₃), Aluminum Nitride (AlN) or Beryllium Oxide (BeO), or substrates requiring special shapes, vias, and unique patterning for microwave applications, this guideline provides the user with a tool to facilitate the design process.

The wide array of thin film capabilities provides solutions for applications serving many markets, including military, automotive, instrumentationmicrowave, telecommunications/CATV/fiber optic, wireless, aerospace, and medical.

Selection Roadmap

The design process begins with the engineer reviewing all the options available to achieve a balanced effective layout, and selecting the best fit in terms of substrate choices, metallization schemes, and interconnection technology. Generally the design process works from the substrate up or out so the first choice would be the substrate. From here the first metal layer is Derek Coulton Vishay Intertechnology 111 Gilbane Street Warwick, Rhode Island 02886 Phone: 401-738-9150 Fax: 401-738-4389 Dcoulton@electro-films.com

designed, making all the major routing connections. Next, any resistors must be placed, giving considerations to power required and the cell size consumed. All resistors should be placed on the substrate surface either front side or back. If front-to- back routing seems appropriate, then through-hole considerations must be addressed as either solid-filled or plated-through.

Next, considerations for placement of other types of components must be addressed. Capacitors, air crossover, and Lange couples must be integrated into the circuit using additional layer routings as required. Figure 1 provides a pictorial view of the selection process.

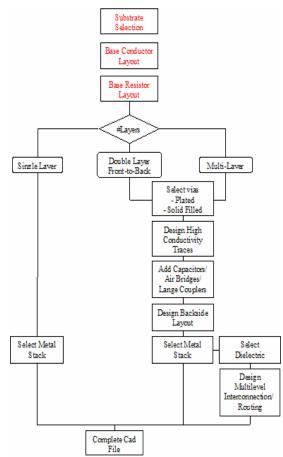


Figure 1. Selection Roadmap

Substrate Characterization

One of the most critical choices in any circuit is the base material on which the circuit is built. As in all designs, the application (Table 1) largely drives the base requirements. The substrate characterization table (Table 2) summarizes many of these choices. Among the primary considerations is the power dissipation required for the circuit. For DC circuits this is a simple choice, but for applications requiring higher frequencies the dielectric constant becomes paramount when frequency response becomes a major consideration. The mechanical properties table (Table 2) summarizes basic characteristics of all the materials compatible with the Vishay process.

| Material | Uses | Benefits |
|---|--|--|
| Quartz (SiO ₂) | Microwave/Millimeter-wave low power/low shunt capacitance | Good for high density patterns / Low loss tangent/low CTE- but more costly |
| Alumina (Al ₂ 0 ₃) | Std hybrid or medium power microwave | Best cost effective choice |
| Aluminum Nitride (AlN) | High power Microwave | Ideal CTE match to silicon devices-high thermal conductivity |
| Silicon | DC circuit- medium/high power | Best choice for high density fine line interconnections |
| Beryllia (BeO) | High power DC/RF/Microwave | Highest Thermal conductivity |

Table 1. Uses and Benefits of Various Substrate Types

| Material | Surface Finish (uin Cla) | STD Thickness Mils(mm) | Available Thickness Mils(mm) | Available Sizes Inches | Diel. Constant ξr @1mhz | TC (W/M °C) 25C/100°C | CTE (ppm/ °C) | Tanð 1MHz 10 Ghz |
|-----------|--------------------------------|------------------------------|------------------------------------|------------------------------|-------------------------------|-----------------------------|------------------|------------------------|
| | $\frac{(um Cia)}{60/40}$ | () | 5–40mil | 3", 5" | <u><u></u>3.82</u> | <u>23C/100 C</u> 5/2 | 0.55 | 0.00002 |
| Quartz | | 10,20 | | 3,3 | 3.82 | 3/2 | 0.55 | |
| | optical | (0.25,0.5) | (0.12-1.0) | | | | | 0.0001 |
| Al_20_3 | <1 pol | 10,15,25 | 5-60 Mil | 4.5"x3.75" | 9.9 | 35/27 | 7.4 | 0.0001 |
| (99.6%) | <3 asf | (0.25,0.38, | (0.12 - 1.5) | 3"x3" | | | | 0.0003 |
| | | 0.63) | , í | 2"x2" | | | | |
| AlN | <3 pol | 20,25,50 | 10-85 mil | 4.25"x4.25 | 8.6 | 170/130 | 4.6 | 0.001 |
| | 24 asf | (0.5,0.63, | (0.25-2.1) | | | | | 0.002 |
| | | 1.3) | | | | | | |
| Silicon | Thermal | 10,15,25 | 10-25 mil | 3", 5" | 2 | 180/~ | 3.4 | ~ |
| | oxide | (0.25,0.38, | (0.25- | | | | | |
| | | 0.63) | 0.63) | | | | | |
| BeO | <4 pol | 15,25 | 10-60 mil | 2.9"x2.3" | 6.5/ | 300/240 | 9 | 0.0004 |
| (99.5%) | <15asf | (0.38,0.63) | (0.25 - 1.5) | | | | | ~ |

 Table 2. . Substrate Characterization

Base Conductor Layout

The second most important parameter in any circuit design is the conductor routing, where current density and conductor impedance can play an important part in the circuit performance. Conductor lines must be designed to withstand the current required. The resistance of that line, especially on signal paths, must be low enough not to create circuit performance issues (see Figure 2). Table 3 summarizes some current limitations for different metals. Table 4 shows some pattern or dimensional limitations that must be considered in the layout. During this phase of the design, layout considerations may also be given for placement of any through holes. Except for filled vias, the size of the holes required depends on the application. Either a plated through-hole conductor or just a hole for pin alignments may be used.

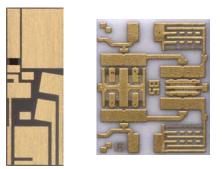


Figure 2. Example of a conductor pattern with special routing for externally mounting components.

| Conductor | | | | Wire bonds >40mil length (1mm) | | | | |
|------------------------------------|----------|----------|--------------------|--------------------------------|-----------|----------------|--|--|
| Max CurrentConductor Width(amps) * | | Diameter | Max Current (amps) | Max Current (amps) | | | | |
| m | ils (mm) | Gold | Alum | mils (mm) | Gold (Au) | Alum Wire (Al) | | |
| 1 | (0.0254) | 0.38 | 0.075 | 0.7 (0.170) | 0.38 | 0.28 | | |
| 5 | (0.127) | 1.9 | 0.38 | 1 (0.025) | 0.65 | 0.48 | | |
| 10 | (0.254) | 3.8 | 0.76 | 2 (0.051) | 1.83 | 1.36 | | |
| 15 | (0.381) | 5.8 | 1.16 | 5 (0.013) | ~ | 5.37 | | |
| 20 | (0.508) | 7.7 | 1.54 | 10 (0.245) | ~ | 15.2 | | |
| 25 | (0.635) | 9.6 | 5.00 | 15 (0.381) | ~ | 27.9 | | |

*Based on Mil-H-38534 Au @ 100u inches-25.4kA thickness; Al @ 50u inches

Table 3. Base Conductor Layout

| Conductor width | Std: 0.002" 0.001 available |
|----------------------|--------------------------------------|
| | (0.05 to 0.025mm) |
| Conductor Line | 50 to 300uinches Au (12.7kA to |
| thickness | 76.2kA) |
| | Std: 0.002 inches Cu 0.006 available |
| | (0.05 to 0.15mm) |
| Line width Tolerance | 0.0001 inches @ 150 u inches |
| | (0.025mm) |
| Though Hole Minimum | 0.005 inches dependent on substrate |
| Diameter | thickness |
| | (0.125 mm) |
| Through Hole | +/-0.002 inches (0.05mm) |
| Tolerance, | |
| Diameter, Position | |
| Metalized hole | 0.8 minimum or greater preferred |
| Diameter | |
| To thickness ratio | |

Table 4. Pattern and Dimensional Layout Considerations

Base Resistor Layout Resistor Range and Sheet Resistance

The choice of resistors is dependent on factors such as resistor material, power, TCR, tolerance, and application. All these factors should be known prior to layout design.. The basic building blocks for any resistor are shown in Figure 4, while Tables 5a, 5b, 5c, and 6 show material options, resistance ranges, and power current density guidelines.

Application such as microwave or simple DC can affect the choice of the layout. Microwave applications are the most restrictive in design format and available resistance values ranges. Fortunately most microwave requirements require lower value resistors.

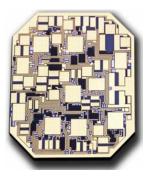


Figure 3. Resistor conductor pattern with 53 resistors for mounting in a special sized package.

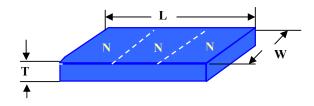


Figure 4. Basic Resistor Building Blocks

$$\begin{split} N &= L/W = \text{Number of Squares (Three in this case)} \\ P &= \text{Intrinsic Resistivity in } \Omega\text{-cm} \\ R_s &= \text{Sheet Resistance } p/t \text{ in } \Omega \text{ / Square} \\ R &= \text{Resistance } p \text{ x } L/W \text{t or } n \text{ x } R_s \text{ in ohms} \\ \text{Rmax} &= A \text{ x } R_s/W^2 \end{split}$$

Although resistance range varies sheet resistivity, it is determined primarily by pattern geometry. Maximum values attainable is limited by available area (A).

| Resistor Material | | Tantalum Nitride | | Nichrome | |
|------------------------------------|------------------------|------------------|--------|----------|---------------------------|
| Sheet Resistance Ω / Square | Nom | 10-50 | 50-100 | 100-200 | Std (10-250 Custom) |
| | Sputtered Tolerance | ±15% | ±20% | ±30% | ±20% |
| Absolute TCR PPM / C | | ±25, 50 | ±100 | ±200 | ±15, +-25, +-50, +-100 |

Table5a. Available Film Systems

| Range | 5 ohm to 2 meg |
|-----------|--------------------|
| Abs. Tol | 5% to 0.1% |
| Ratio Tol | 1% to 0.01% (range |
| | dependent) |

Table 5b. Standard Resistor Parameters

| Range | 10 ohm -1k ohm |
|--------------|----------------|
| Abs. Tol | 0.5% |
| Ratio Tol | 0.5% |
| Absolute TCR | <=200ppm |

 Table 5c. Microwave Resistor

 Parameters

| Sheet Resistance | Al ₂ O ₃ | Silicon | Quartz | ALN | BEO |
|------------------|--------------------------------|-----------------------|----------------------------|--------------------------|------------------------|
| @ 25 ohms/sq | 4 ma/mil | 20 ma/mil line width | 0.5 ma/mil line | 19 ma/mil line | 32 ma/mil line |
| | line width | | width | width | width |
| @ 50 ohms/sq | 2 ma/mil | 10 ma/mil line width | 0.25 ma/mil line | 9.5 ma/mil line | 16 ma/mil line |
| | line width | | width | width | width |
| @ 100 ohms/sq | 1 ma/mil | 5 ma/mil line width | 0.125 ma/mil | 4.7 ma/mil line | 8 ma/mil line |
| | line width | | line width | width | width |
| @ 200 ohms/sq | 0.5 ma/mil line width | 2.5 ma/mil line width | 0.062 ma/mil line width | 2.3 ma/mil line width | 4 ma/mil line width |

 Table 6. Power Current Density vs. Material and Film Selection. The lower the sheet resistivity, the higher the current density.

Microwave Resistor Design

Ideal resistor design for microwave applications evolves from a stripline format where resistor layout is simply a rectangle without any cuts that could cause reflection and affect VSWR characteristics. In practice, unless resistor tolerance is loose, most manufacturers require trimming to maximize yields. To minimize the affects of trimming, utilize edge sense trimming for these resistors around a centerline to maintain frequency response (Figure 5). Current inspection criteria allows up to 50% of the resistor to be removed. The use of a high-temperature stabilization procedure produces very stable resistors and minimizes drift over time or temperature.

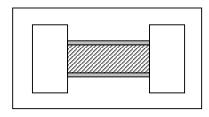


Figure 5. Stripline format for resistor layout.

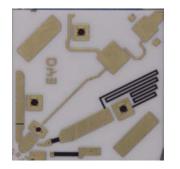


Figure 6. A typical microwave design.

Cutouts and Special Shapes

For many applications it is necessary to have a substrate fit into a particular cavity or allow cutouts for component placement of die planer with the substrate surface. With Co_2 cutting, almost any shape from round discs to a complex U shaped structure with multiple hole placements can be achieved (Figure 7).

This technology allows us to do our own in-hole drill for plated through holes, filled vias, edge-wrap metallization, and two sided-substrate patterning.

| Parameter | | | | |
|----------------------|----------------------|--|--|--|
| Substrates | Alumina, Aln, Beo, | | | |
| | Quartz | | | |
| Position Tol | +/-0.003" (0.076mm) | | | |
| Substrate Edge to | 0.002" min (0.05 mm) | | | |
| circuit | | | | |
| Inside Corner Radius | 0.005" min (0.127mm) | | | |
| % of substrate | 25% | | | |
| removal | | | | |

Table 7. Laser Machining Capability

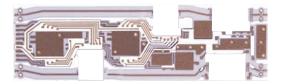


Figure 7. With Co₂ cutting, almost any shape from round discs to a complex U shaped structure with multiple hole placements can be achieved.

Layers

In general, the size required by the application will determine the number of layers: single, two-sided or multilayer. Applications that limit size are the most demanding to lay out, compelling the designer to use a two-sided or multilayer solution (Figure 7). It's most cost effective to manufacture as a single layer whereever possible. At this point consideration must be taken for conducter routing, vias, resistor cell, added actve devices, special features such as capacitors, Lange couples and any asociated interconnects. High-density and multilayer design require complexity and a close relationship to end product performance to assure optimum performance. The use of a cad systems can steamline design difficulties. Table 8 lists the various layer applications and metal choices for each. Where mutiple choices exist, compatability with other metals must be analyzed, and choices are given in Table 9.



Figure 8. Typical substrate with combination of thin gold and thick copper/gold areas for solder attach or high-current applications.

| | | Std Sputter | Std Plated | |
|--------------|---|-------------|----------------|---------------------|
| Layer | Material | Thickness | Thickness | Comments |
| Adhesion | Titanium-Tungsten (TiW) | 500Å min | ~ | |
| | Titanium (Ti) | 500Å min | ~ | |
| | Nichrome (NiCr) | 500Å min. | ~ | |
| | Chrome (Cr) | 500Å min | ~ | |
| | Tantalum Nitride (Ta ₂ N) | 300Å min | ~ | High temp barrier |
| Barrier | Palladium (Pd) | 3kÅ- 5kÅ | ~ | High temp barrier |
| | Tiw | 500Å-1kÅ | ~ | High temp barrier |
| | Nickel (Ni) | 1.5kÅ- 5kÅ | 5kÅ-15kÅ | |
| Conductor | Aluminum (Al) | 10kÅ min | ~ | |
| | Gold (Au) | 1kÅ-3kÅ | 25.4kÅ min | |
| | Copper (Cu) | 4-12u | 15-45u inches | |
| | | (1kÅ-3kÅ) | (3.8kÅ-11.4kÅ) | |
| | Gold (Au) | ~ | 300u inches | |
| High Current | | | (76.2kÅ) | Min |
| Conductor | Copper (Cu) | ~ | 1000u inches | |
| | | | (254kÅ) | |
| Dielectric | Silicon Nitride (Si ₃ N ₄) | 2kÅ-5kÅ | ~ | Diel. Constant= 6-9 |
| | Polyimide | 48kÅ +/-1kÅ | | Diel. Constant= 3.4 |

Table 8. Typical Film Thickness

| Metal stack | Layers | Max | S | olderable | Wire Bondable | Braze-able |
|------------------------------|--------|----------|------|-----------|---------------|------------|
| | Single | exposure | Gold | Solder | | |
| | Double | | | | | |
| | Multi | Temp C | | | | |
| Ta/T _i w/Au | S,D | 450 | 2 | 2 | yes | |
| Ta/T _i w/Au/Ni/Au | S,D | 350 | Yes | Yes | Yes | Yes |
| Ta/T _i w/Pd/Au | S,D | 450 | Yes | Yes | Yes | |
| Ta/Pd/Au | S,D | 400 | Yes | Yes | Yes | |
| Ta/Ni/Au | S,D | 350 | 2 | Yes | Yes | |
| Ta/Tiw/Au/Cu/Au | S,D | 300 | 2 | 2 | Yes | |
| Ta/Tiw/Au/Cu/Ni/Au | S,D,M | 300 | Yes | Yes | Yes | Yes |
| Nicr/Au | S,M | 350 | 2 | 2 | Yes | |
| Nicr/T _i w/Au | S,D | 400 | 2 | 2 | Yes | |
| Nicr/Au/Ni/Au | S,D | 350 | Yes | Yes | Yes | |
| Nicr/Ni/Au | S,D | 350 | Yes | Yes | Yes | |
| T _i w/Au | S,D,M | 400 | ~ | ~ | Yes | |
| T _i w/Au/Ni/Au | S,D | 350 | Yes | Yes | Yes | |
| T _i w/Pd/Au | S,D | 400 | Yes | Yes | Yes | |
| Ti/Pd/Au | S,D,M | 350 | Yes | Yes | Yes | |
| Cr/Ni/Au | S,D,M | 350 | Yes | Yes | Yes | |

Table 9. Metal Stack Options

Selecting Through-Hole Vias

The choice between plated through-hole vias and filled vias is a matter of application. The least expensive choice is the plated through-hole, where only a simple front-to-back electrical path is required.

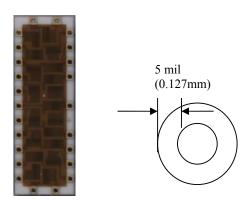
Filled vias are often the choice when improved thermal conductivity to the backside is needed. They offer the designer as many heat channels as the area allows. A filled via also allows the component engineer to place components directly over the via for maximum heat transfer from the component. Filled vias can be used to provide additional low thermal conductivity paths to ground plate heat sinks to improve signal transmission.

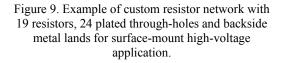
Through-hole patterns require a minimum of a 0.005 mils ring around each hole to compensate for the tolerance build-up caused by hole placement, manufacturing alignment, diameter tolerances, the slight laser entrance hole rounding, and other factors (see Figure 9).

Plated through-hole designs require a 0.8 x substrate thickness minimum with typical impedance of less than 20 milliohms (Figure 9). Filled vias require a diameter of 7 ± 2 mils (0.18 \pm 0.05 mm) with typical impedance of less than 3

milliohms. With Co2 cutting, almost any shape from round discs to a complex U shaped structure with multiple hole placements can be achieved.

Edge wraparound connections are also another option to consider when designing connections to backside plane.





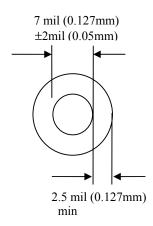


Figure 10. Filled Vias

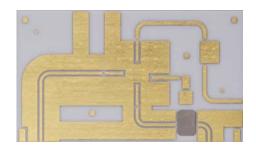


Figure 11. Example of conductor pattern with filled vias.

Air or Polyimide Suport Bridges and Lange Couplers

When crossovers are necessary, air bridges can be configured on the conductor pattern. A sacrificial layer is deposited and patterned before the second layer is put in place. The intermediate layer is then removed leaving the complete air bridge. The same process can be done for a supported air bridge using polyimide; in this case, the polyimide layer remains in place on the finished part. Bridges supported by polyimide provide a more rugged structure.

Dimensional limits are as follows:

Minimum Gap between lines: 0.5 mils (0.0127mm) Tolerance: +/-0.1mil (0.00254 mm) Minimum line width 0.5 mil (0.0127mm) Tolerance: +/-0.1mil (0.00254mm)

Bridge Height: 300-500 u inches

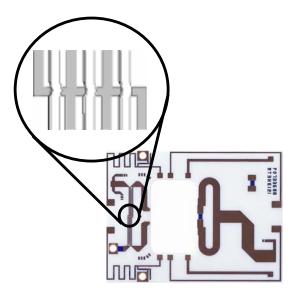


Figure 12. An example of a polymide support bridge.

Solder Dam

For many applications the need arises to place components on the substrate with epoxy, or with solder, if tight planerization is needed. This is true particularly in fiber optic sub-mount assemblies. Solder dams can be offered as either polyimide or a lower temperature thermal set plastic.

Backside Layout

Conductor interconnect patterns or ground plane definition can be provided on the bottom surface of the substrate. Front-to-back alignment can be held to 0.002 inches (0.051mm). The backside metallization can also provide shielding for inter conductor layers in multilayer designs. The design shown in Figure 13 combines several feature available using thin film techniques with the backside pattern options: metalized through holes for grounding, large area metal for low impedance, and a custom shape. Backside patterning allows designer a cost-effective alternative to a top-surface multilayer design.

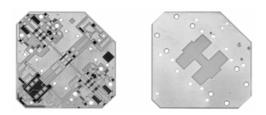


Figure 13. Front and backside patterned array.

Multi-Layer

For designs that require more layers than the single-layer front or back combination can offer, the designer may stack layers on either side in a multilayer arrangement. The use of dielectric material such as polyimide or silicon nitride as an insulating layer between metal layers becomes a primary concern, as shown in Table 10. The most commonly used is polyimide because of its patterning properties and processing temperatures.

| Layer | Material | Std. Thickness | Comments |
|------------|--------------------|-------------------|----------------------------|
| Dielectric | Polyimide | 2kÅ-5kÅ | Diel. Constant = 6-9 |
| | Silicon Nitride | 48kÅ ±1kÅ | Diel. Constant = 3.4 |

Table 10. Dielectric Parameters

The board space saved by taking this approach is summarized in Table 11. This is an approximation since there are many factors that can affect area usage.

Usually no stacking restrictions apply when using the dielectrics listed in Table 10. However, process compatibility issues between layers may restrict the use of multiple metal stacks on multiple dielectric layers. The easiest way to determine your option is to forward what you think is needed and the engineering staff will review it.

| Multilayer Area Savings Chart Per Layer | |
|--|--------------------|
| # of layers | Approx area factor |
| | reduction |
| 1 | 1.33 |
| 2 | 1.77 |
| 3 | 2.37 |
| 4 | 3.16 |

Table 11. Area Savings Per Layer

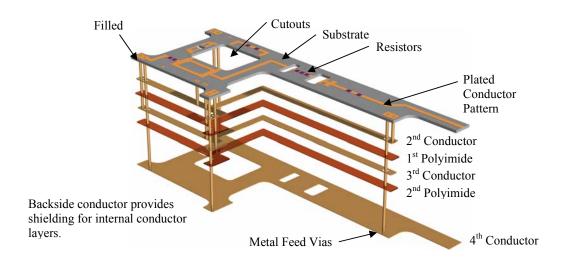


Figure 14. Expanded View of a Thin Film Multilayer HDI Circuit

An actual design from a military helicopter used almost all the design/process option available and after significant R&D effort was manufactured with reasonable yields (Figure 14).

Cad Design and Layout

Except for microwave applications where sophisticated circuit modeling is required, Vishay can develop passive circuit layout based on inputs received in schematic format or from rough outline drawings.

The minimum information needed is detailed in the list below. Vishay can also offer hybrid design layout services if parts lists are available.

Design Inputs Schematic or layout Min./Max substrate size Resistor Tol's/ratio Tol's TCR /TC track Power per resistor Metallization Preference

Summary

Many issues affect the layout of complex designs. To achieve the best balance for your application, differences in material, size, and performance must be taken into account and reflected in the specification and final layout. It is recommended to work closely with your manufacturer to establish a balanced workable design and to consider all the critical process criteria. When properly designed overall quality and performance can be enhanced to accomplish your goals.

The guideline shown in Figure 15 summarizes the layout design criteria.

References: Thin Film Technology Handbook. Aicha A.R. Elshabini-Riad, Fred D. Bartlow III, McGraw Hill 1998.

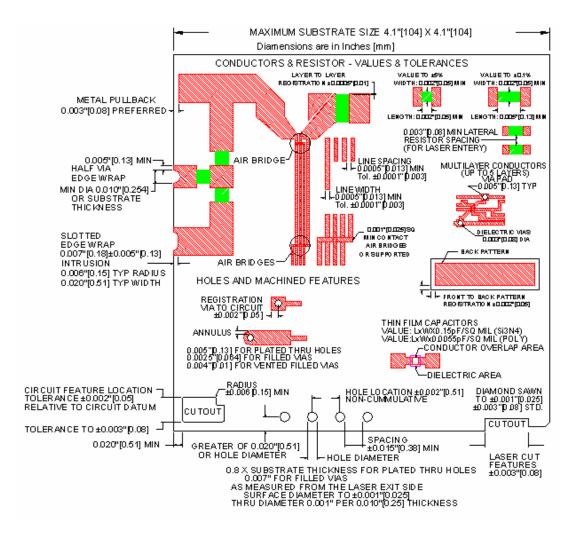


Figure 15. Standard Layout Guidelines